

Search Notes

Application/Control No.

10/757,420

Examiner

EDMUND H. LEE

Applicant(s)/Patent under
Reexamination

YAMAKAWA ET AL.

Art Unit

1732

SEARCHED

Class	Subclass	Date	Examiner
264	162	6/26/2006	EHL
	161		
83	13		

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner

**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
east	6/26/2006	EHL
inventor		